

Notice of References Cited

Application/Control No.

10/532,434

Applicant(s)/Patent Under

Reexamination

CHOI, UNHO

Examiner

MICHAEL R. VAUGHAN

Art Unit

2431

Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-6,343,362 B1	01-2002	Ptacek et al.	726/23
*	B US-2002/0199122 A1	12-2002	Davis et al.	713/201
*	C US-2003/0028803 A1	02-2003	Bunker et al.	713/201
*	D US-6,574,737 B1	06-2003	Kingsford et al.	726/25
*	E US-6,952,779 B1	10-2005	Cohen et al.	726/22
*	F US-6,957,348 B1	10-2005	Flowers et al.	726/23
*	G US-7,047,423 B1	05-2006	Maloney et al.	726/2
*	H US-7,073,198 B1	07-2006	Flowers et al.	726/25
*	I US-7,325,252 B2	01-2008	Bunker et al.	726/25
*	J US-7,549,168 B1	06-2009	Magdych et al.	726/25
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	Chung, M., Puketza, Olsson and Mukherjee, Simulating Concurrent Intrusions for Testing Intrusion Detection Systems: Parallelizing Intrusions. Proc. of the 1995 National Information Systems Security Conf. Baltimore, Maryland, pp: 173-183.
V	W. Puketza, K. Zhang, M. Chung, B. Mukherjee, and R. Olsson. A Methodology for Testing Intrusion Detection Systems", IEEE Transactions on Software Engineering, 1996, 22(10), pages: 719-729.
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.